Correlation between structural and optical properties of SiO2/TiO2multibilayers processed by sol-gel technique and applied toBragg reflectors

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Abstract: SiO2 and TiO2 thin layers processed by sol-gel technique have been deposited, alternatively, on glass substrates and Si (111) wafer. Dip-coatedmultibilayerswere characterized by different experimental techniques: XRD, SEM, FTIRandUV-VIS-NIR. The obtainedX-ray diffraction patterns analysishave shown that our films crystallize in anatase and rutile phases whateveris the number of bilayers and the corresponding grain sizes increasefrom 5.48 nmto 16.11 nm. The SEMmicrograph shows that our layers arehomogeneous without any visual cracks. The FTIR spectra have shownthat the vibration of Si-O-Ti bonds becomes intense by the increase in thenumber of bilayers. This increase, on the on hand, decreases the transmissioncoefficient from 4.58% to 0.55% and increases the width of the stopband shown in UV-VIS-NIR spectra. On the other hand, the band-gap decreasesfrom3.73 eV to 3.59 eV. In addition, a pseudo band-gap is locatedbetween 300 nmand 400 increasing from1.76 eVto 2.29 eV.? 2013 Trade Science Inc. - INDIA

Keywords: Sol-gel;, Anatase;, Rutile;, Stop band;, Si-O-Ti;, Band-gap.